四路低功耗差动接收器

查询样品: SN55LBC173-DIE

特性

- 符合 **EIA** 标准 **RS-422-A**，**RS-423-A**，**RS-485** 和 **CCITT V.11**
- 被设计成支持脉冲时长运行
- 针对嘈杂环境中的长距离总线线路上的多点总线传输
- 低功耗
- 开电路故障安全设计

说明

SN55LBC173-DIE 是一款具有 3 态输出的单片四路差动线路接收器，此接收器被设计成符合 EIA 标准 RS-422-A，RS-423-A，RS-485 和 CCITT V.11。 这个器件在数据速率方面针对均衡多点总线传输进行了优化。 4 个接收器共用 2 个进行或操作的使能输入，一个在高电平时有效，一个在低电平时有效。 每个接收器特有用来增加抗扰度的高输入阻抗、输入滞后。 故障安全设计确保了在输入为开电路时，输出一直为高电平。 SN55LBC173-DIE 使用德州仪器 (TI) 已获专利的 LinBiCMOSE™ 技术进行设计，这个技术提供了低功耗、高开关速度和稳健耐用性。

ORDERING INFORMATION(1)

PRODUCT	PACKAGE DESIGNATOR	PACKAGE	ORDERABLE PART NUMBER	PACKAGE QUANTITY
SN55LBC173	TD	Bare die in waffle pack(2)	SN55LBC173TDA1	100
			SN55LBC173TDA2	10

(1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at www.ti.com.

(2) Processing is per the Texas Instruments commercial production baseline and is in compliance with the Texas Instruments Quality Control System in effect at the time of manufacture. Electrical screening consists of DC parametric and functional testing at room temperature only. Unless otherwise specified by Texas Instruments AC performance and performance over temperature is not warranted. Visual Inspection is performed in accordance with MIL-STD-883 Test Method 2010 Condition B at 75X minimum.

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

LinBiCMOSE is a trademark of Texas Instruments.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of the Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

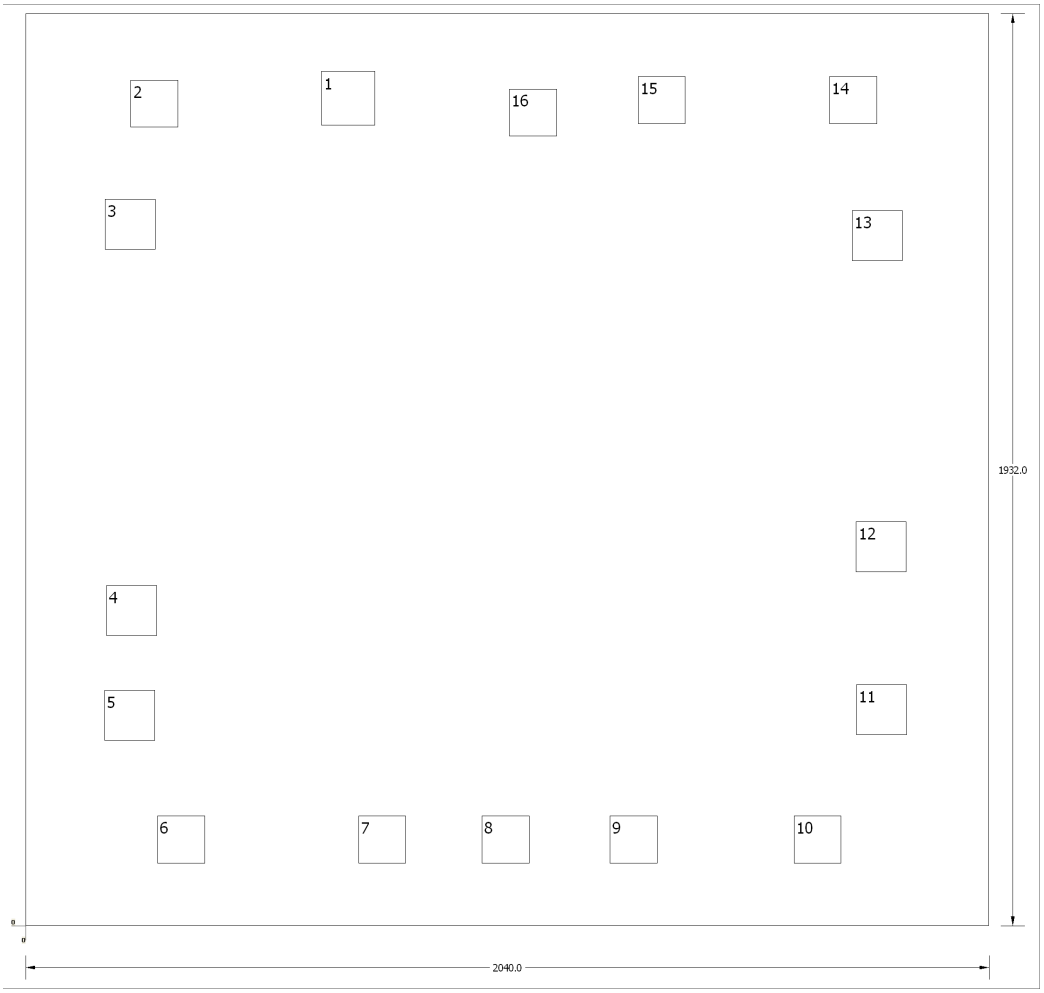
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This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

BARE DIE INFORMATION

DIE THICKNESS	BACKSIDE FINISH	BACKSIDE POTENTIAL	BOND PAD METALLIZATION COMPOSITION	BOND PAD THICKNESS
10.5 mils.	Silicon with backgrind	Floating	AlSi(1%)Cu(0.5%)TiW	1850 nm



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Table 1. Bond Pad Coordinates in Microns

DESCRIPTION	PAD NUMBER	X MIN	Y MIN	X MAX	Y MAX
1B	1	626.5	1695	740.5	1809.5
1A	2	222.5	1690.7	323	1791.3
1Y	3	167.9	1432.1	274.8	1539
G	4	171.4	614.1	278.3	721
2Y	5	166.6	392.1	273.5	499
2A	6	279.2	132	379.7	232.6
2B	7	704.8	132	805.3	232.6
GND	8	966.2	132	1066.7	232.6
3B	9	1237.2	132	1337.7	232.6
3A	10	1626.7	132	1727.2	232.6
3Y	11	1758.7	403.7	1865.6	510.6
$\overline{G}$	12	1758.5	749	1865.4	855.9
4Y	13	1750.1	1408.4	1857	1515.3
4A	14	1702.2	1698.4	1802.7	1799
4B	15	1296.7	1698.4	1397.2	1799
VCC	16	1024.2	1671.9	1124.7	1772.5

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PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
SN55LBC173TDA1	LIFEBUY			0	100	RoHS & Green	Call TI	N / A for Pkg Type	25 to 25		
SN55LBC173TDA2	LIFEBUY			0	10	RoHS & Green	Call TI	N / A for Pkg Type	25 to 25		

(1) The marketing status values are defined as follows:
ACTIVE: Product device recommended for new designs.
LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
PREVIEW: Device has been announced but is not in production. Samples may or may not be available.
OBSOLETE: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".
RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.
Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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